Abstracts

High Frequency Measurement of Dielectric Thin Films

P.K. Singh, R.S. Cochrane, J.M. Borrego, E.J. Rymaszewski, T.M. Lu and K. Chen. "High Frequency Measurement of Dielectric Thin Films." 1994 MTT-S International Microwave Symposium Digest 94.3 (1994 Vol. III [MWSYM]): 1457-1460.

A test vehicle was designed that enabled the measurement of the dielectric constant and loss tangent of thin dielectric films from 1 KHz to 40 GHz. The test vehicle consists of a metal-dielectric-metal parallel plate structure. The measurements were made with a LCR meter and a network analyzer.

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